

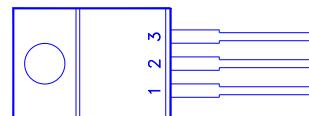
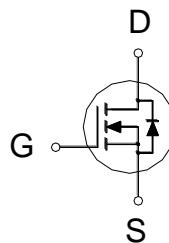
**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P1610AT**

TO-220

Halogen-Free &amp; Lead-Free

**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
110V	16mΩ	51A


 1.GATE  
 2.DRAIN  
 3.SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>2</sup>	$T_C = 25^\circ\text{C}$	$I_D$	51	A
	$T_C = 100^\circ\text{C}$		32	
Pulsed Drain Current <sup>1,2</sup>		$I_{DM}$	150	
Avalanche Current		$I_{AS}$	12	
Avalanche Energy	$L = 1\text{mH}$	$E_{AS}$	72	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	96	W
	$T_C = 100^\circ\text{C}$		38	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		1.3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Limited only by maximum temperature allowed.**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	110			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2	3.2	4	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 88\text{V}, V_{GS} = 0\text{V}$			1	$\mu\text{A}$
		$V_{DS} = 80\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	

**NIKO-SEM****N-Channel Logic Level Enhancement  
Mode Field Effect Transistor****P1610AT**

TO-220

Halogen-Free &amp; Lead-Free

Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 7V, I_D = 15A$	14	21	$m\Omega$
		$V_{GS} = 10V, I_D = 20A$	13	16	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 10V, I_D = 20A$	80		S
<b>DYNAMIC</b>					
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$	3009		$pF$
Output Capacitance	$C_{oss}$		258		
Reverse Transfer Capacitance	$C_{rss}$		152		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$	0.81		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = 55V, V_{GS} = 10V, I_D = 20A$	57		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		15.8		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		20		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DD} = 55V$ $I_D \geq 20A, V_{GS} = 10V, R_{GEN} = 6\Omega$	47		$ns$
Rise Time <sup>2</sup>	$t_r$		88		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		86		
Fall Time <sup>2</sup>	$t_f$		83		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ C</math>)</b>					
Continuous Current	$I_S$	$I_F = 20A, V_{GS} = 0V$		51	A
Forward Voltage <sup>1</sup>	$V_{SD}$			1.2	V
Reverse Recovery Time	$t_{rr}$		37		$ns$
Reverse Recovery Charge	$Q_{rr}$		50		$nC$

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.

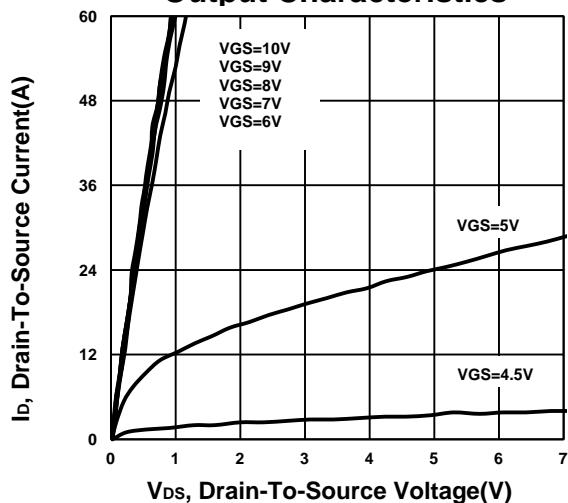
**NIKO-SEM**

**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**

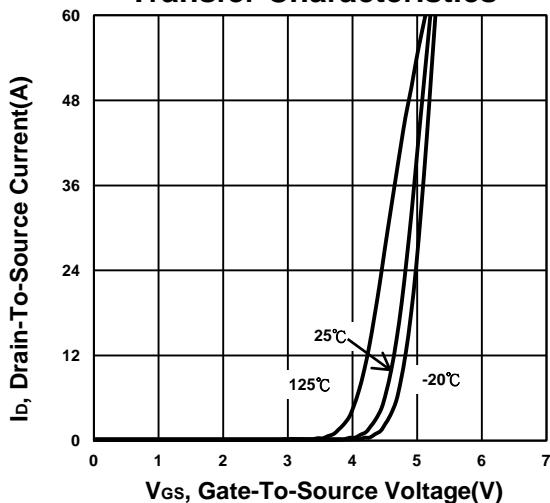
**P1610AT  
TO-220**

**Halogen-Free & Lead-Free**

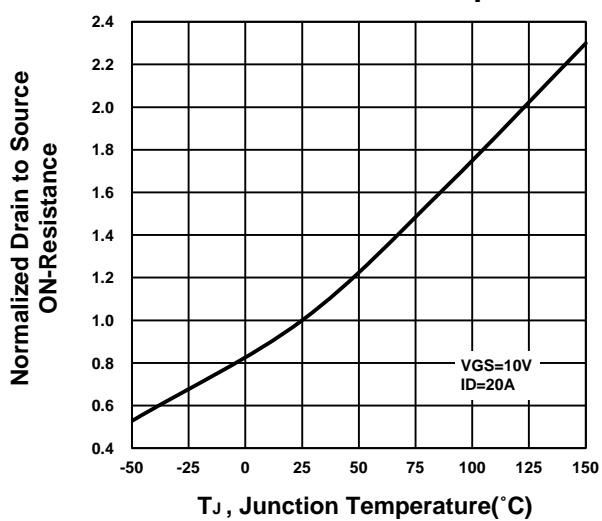
### Output Characteristics



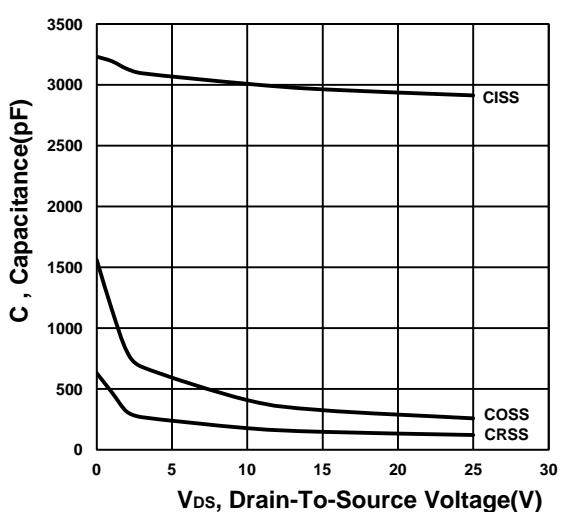
### Transfer Characteristics



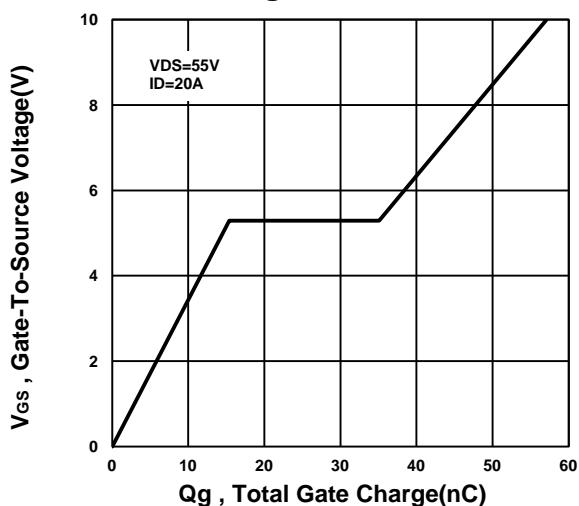
### On-Resistance VS Temperature



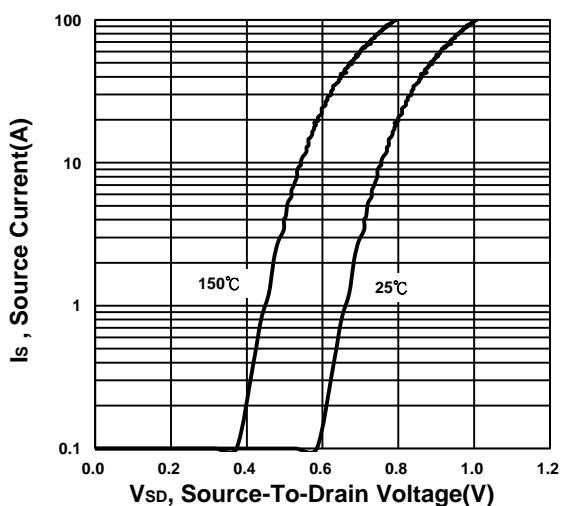
### Capacitance Characteristic



### Gate charge Characteristics



### Source-Drain Diode Forward Voltage



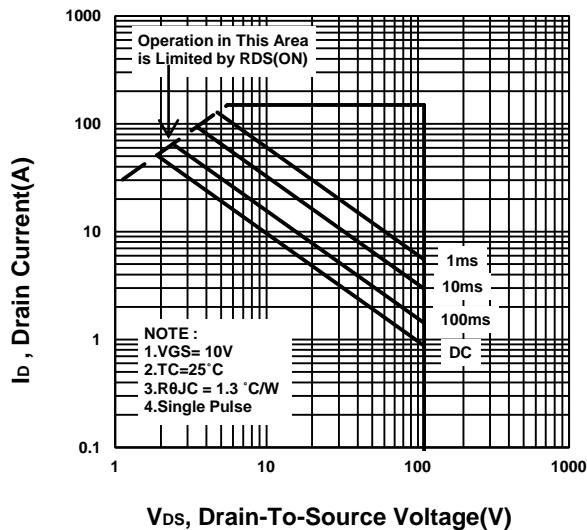
**NIKO-SEM**

**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**

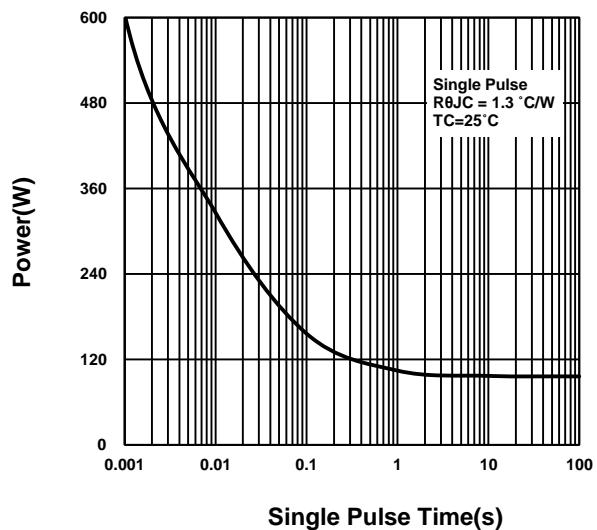
**P1610AT  
TO-220**

**Halogen-Free & Lead-Free**

### Safe Operating Area



### Single Pulse Maximum Power Dissipation



### Transient Thermal Response Curve

